12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN 20160630001
DFAB VLCT Offload to SCT
Final Change Notification

Date: December 13, 2016
To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an initial announcement of change to a device that is currently offered by Texas Instruments. A final announcement with qualification data, as applicable, will be provided when available. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

If additional data are required, requests must be received within 30 days of acknowledgement. You may contact the PCN Manager or your local Field Sales Representative to acknowledge this PCN or request additional data.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_ww_admin_team@list.ti.com).

Sincerely,

PCN Team
SC Business Services

20160630001
Final Change Notification
Attachments

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
SN65HVD1050AQDRQ1	null
SN65HVDA1050AQDRQ1	null
TPA6211A1TDGNRQ1	null
SN65HVD1050QDRQ1	null
TPIC6C595DR	null
TPIC74100QPWPRQ1	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20160630001	**PCN Date:**	Dec 13, 2016
Title:	DFAB VLCT Offload to SCT		
Customer Contact:	PCN Manager	**Dept:**	Quality Services
Proposed 1st Ship Date:	June 13, 2017		
Change Type:			

☐	Assembly Site	☐	Design	☐	Wafer Bump Site
☐	Assembly Process	☐	Data Sheet	☐	Wafer Bump Material
☐	Assembly Materials	☐	Part number change	☐	Wafer Bump Process
☐	Mechanical Specification	☒	Test Site	☐	Wafer Fab Site
☐	Packing/Shipping/Labeling	☐	Test Process	☐	Wafer Fab Materials
				☐	Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments Incorporated is announcing the transfer of select high volume demand devices using VLCT tester in DFAB (Dallas South bldg. North Campus) to VLCT tester EBT/SCT (Dallas SC Building in North Campus).

Test programs are identical.

Test hardware configurations identical.

Reason for Change:

- Consolidate the VLCT tester to one probe facility
- Mitigate test capacity shortage in DFAB.
- Material test cycle time improvement.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

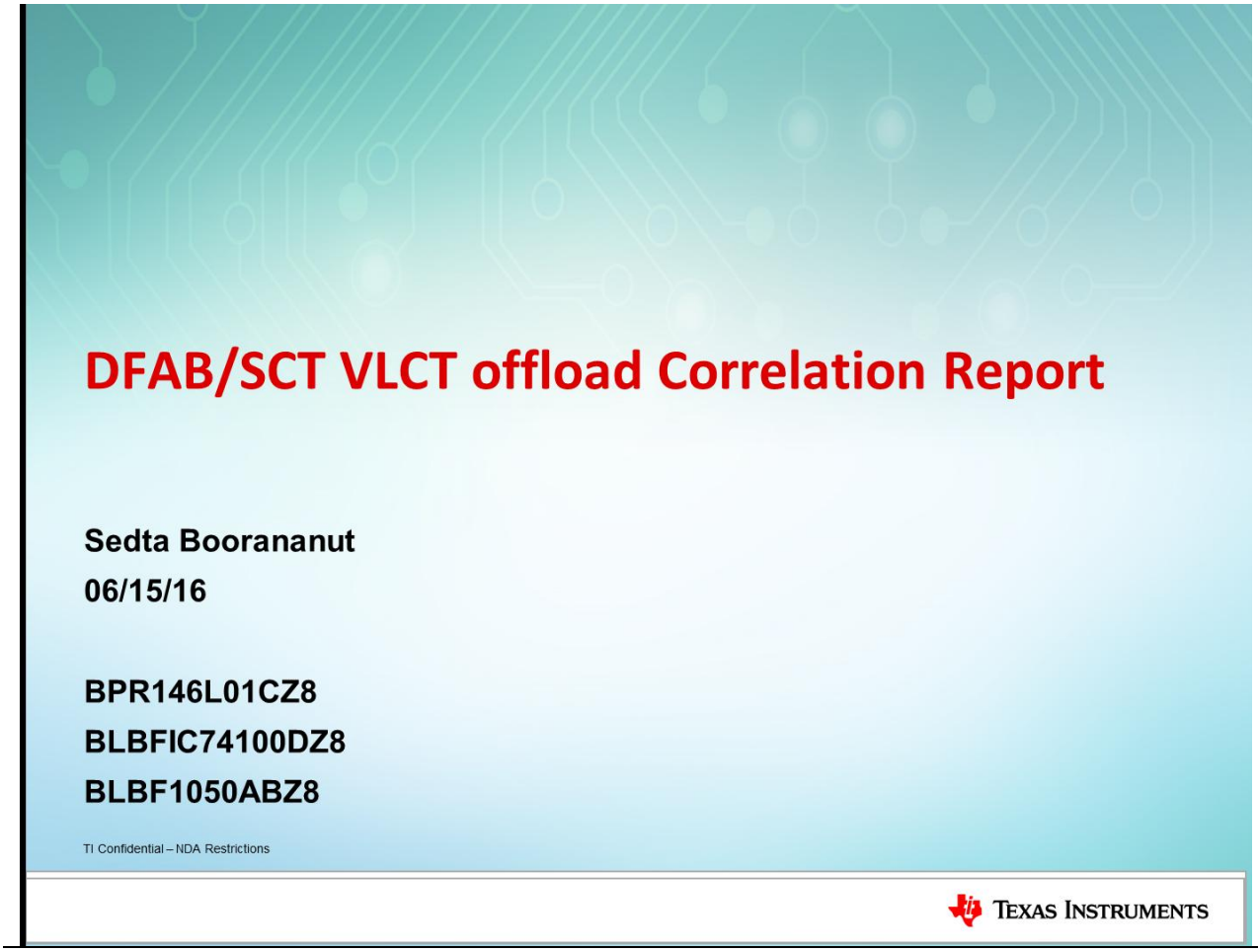
Site	site code (20L)	country code (21L)
DFAB	DFB	USA

New

Site	site code (20L)	country code (21L)
SCT	**DM4**	**USA**

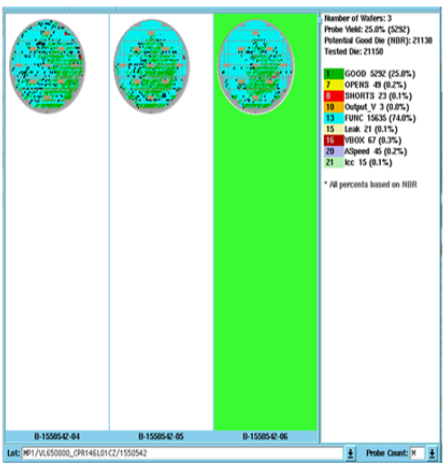
Example shipping label (not actual product label)

Product Affected:			
SN0605104PJ-A	TPIC44L01DBG4	TPIC46L02DBG4	TPIC6C595DR
SN104217NSR-A	TPIC44L01DBR	TPIC46L02DBR	TPIC6C595DRG4
SN104479DWR	TPIC44L02DB	TPIC46L02DBRG4	TPIC6C595N
SN65HVD1040QDRQ1	TPIC44L02DBG4	TPIC6B595DW	TPIC6C595PW
SN65HVD1050AQDRQ1	TPIC44L02DBR	TPIC6B595DWG4	TPIC6C595PWG4
SN65HVD1050QDRQ1	TPIC44L02DBRG4	TPIC6B595DWR	TPIC6C595PWR
SN65HVDA1050AQDR-M	TPIC46L01DB	TPIC6B595DWRG4	TPIC6C595PWRG4
SN65HVDA1050AQDRQ1	TPIC46L01DBG4	TPIC6B595N	TPIC74100QPWPRQ1
TLC5941QPWPRQ1	TPIC46L01DBR	TPIC6C595D	TPIC74100QPWPRLRD
TPA6211A1TDGNRQ1	TPIC46L01DBRG4	TPIC6C595DG4	TPIC74101QPWPRQ1
TPA6211A1TDNVRQ1	TPIC46L02DB		TUSB1106IPWRQ1
TPIC44L01DB			

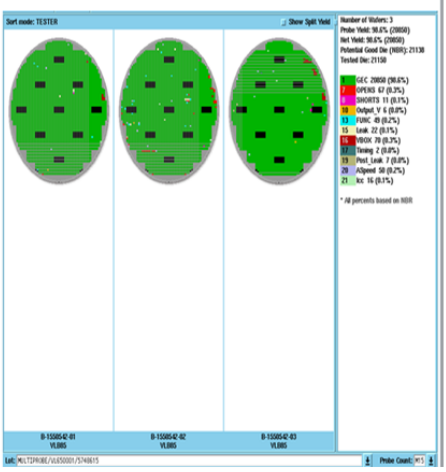


SCT/DFAB Correlation Data– BPR146L01CZ8 offload to SCT

DFAB



SCT



VL650001_TJ3
Parametric Quad Analysis

Cpk>=1.67	Q1: 211 of 253	Q2:
Cpk<1.67(*)	Q3: 24 of 253	Q4:
	< 1.5 Sigma Shift	>= 1.5

- (*) or Cpk < 0.5 X Base Cpk
- Unclassified tests: 7
- Click in a quad to view plots of the tests

- DFAB Yield 25% compared to SCT Yield 98.6%
- SCT has zero GEC due to bin13 on the VL650000 program (original program).
- SCT have to work on the VL650001program to address bin13 issue and address the SCT automation issue (Change Temp type from Temp_25C_Deg to Temp_30C_Deg and add Pin List for Auto-Z routine.
- See the Parametric quad analysis on the follow link http://home.dal.design.ti.com/~a0864045/1550542

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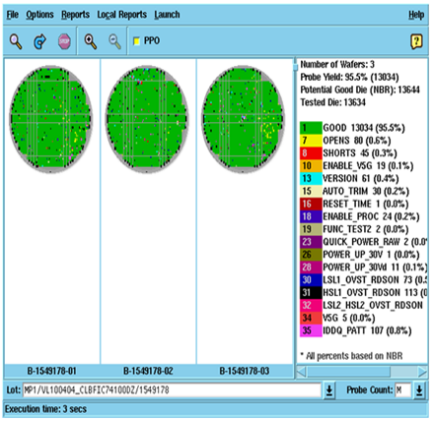
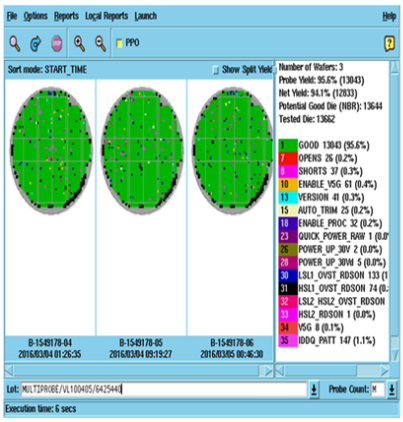
SCT/DFAB Correlation Data– BLBFIC74100DZ offload to SCT

DFAB



SCT



VL100405_FT3
Parametric Quad Analysis

Cpk>=1.67	Q1: 96 of 143	Q2: 2 of 143
Cpk<1.67(*)	Q3: 43 of 143	Q4: 1 of 143
	< 1.5 Sigma Shift	>= 1.5 Sigma Shift

- (*) or Cpk < 0.5 X Base Cpk
- Unclassified tests: 1
- Click in a quad to view plots of the tests.

- DFAB Yield 95.5% compared to SCT Yield 95.6%
- SCT have to modify test program on the VL100405 program to address the SCT automation issue (Change Temp type from Temp_25C_Deg to Temp_30C_Deg and add Pin List for Auto-Z routine.
- See the Parametric quad analysis on the follow link http://home.dal.design.ti.com/~a0864045/1549178
- Most of the parameters shows the low Cpk and relate to the bin13.

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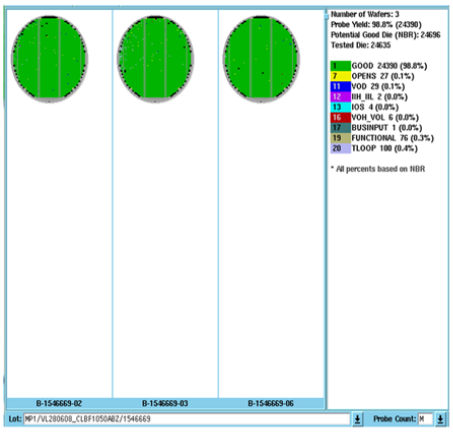
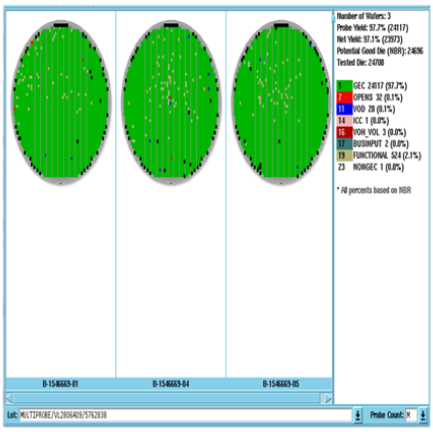
SCT/DFAB Correlation Data– BLBF1050ABZ offload to SCT

DFAB



SCT



VL2806A09_LF4
Parametric Quad Analysis

Cpk>=1.67	Q1: 54 of 80	Q2: 6 of 8
Cpk<1.67(*)	Q3: 4 of 80	Q4: 2 of 8
	< 1.5 Sigma Shift	>= 1.5 Sigma

- (*) or Cpk < 0.5 X Base Cpk
- Unclassified tests: 14
- Click in a quad to view plots of the tests.

- DFAB Yield 98.8% compared to SCT Yield 97.7%
- SCT have to modify test program on the VL280609 program to address the SCT automation issue (Change Temp type from Temp_25C_Deg to Temp_30C_Deg and add Pin List for Auto-Z routine.
- See the Parametric quad analysis on the follow link http://home.dal.design.ti.com/~a0864045/1546669/

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For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com